

EVENT BASED TEST SYSTEM HAVING IMPROVED
SEMICONDUCTOR CHARACTERIZATION MAP

Abstract of the Disclosure

5 An event based test system having [an improved] 6L
characterization tool for semiconductor device testing. The
10 characterization map provides multi-dimensional views of
device performance for debug of the design, and
identification of performance weaknesses. The
characterization map tool exploits the capabilities of the
event based test system. The multi-dimensional views
include a checkerboard map such as displaying pins versus
time, a shmoo plot showing pass-fail boundary points
relative to predetermined parameters, or a margin map
15 showing a pass/fail range for pins corresponding with timing
changes in one or more events.

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